# Tim Grieb

List of Publications by Year
in descending order

Source: https://exaly.com/author-pdf/3858271/publications.pdf

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| 30 | 825 | 471509 17 | 501196 28 |
|---|---|---|---|
| papers | citations | h-index | g-index |

| 35 | 35 | 35 | 1012 |
|---|---|---|---|
| all docs | docs citations | times ranked | citing authors |

| # | Article | IF | Citations |
|---|---|---|---|
| 1 | Measurement of atomic electric fields and charge densities from average momentum transfers using scanning transmission electron microscopy. Ultramicroscopy, 2017, 178, 62-80. | 1.9 | 106 |
| 2 | Determination of the chemical composition of GaNAs using STEM HAADF imaging and STEM strain state analysis. Ultramicroscopy, 2012, 117, 15-23. | 1.9 | 79 |
| 3 | Screening Precursorâ€“Solvent Combinations for Li<sub>4</sub>Ti<sub>5</sub>O<sub>12</sub>Energy Storage Material Using Flame Spray Pyrolysis. ACS Applied Materials & Interfaces, 2017, 9, 37760-37777. | 8.0 | 68 |
| 4 | Effects of instrument imperfections on quantitative scanning transmission electron microscopy. Ultramicroscopy, 2016, 161, 146-160. | 1.9 | 55 |
| 5 | Synthesis Route for the Self-Assembly of Submicrometer-Sized Colloidosomes with Tailorable Nanopores. Chemistry of Materials, 2013, 25, 3464-3471. | 6.7 | 47 |
| 6 | Theoretical study of precision and accuracy of strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2015, 158, 38-48. | 1.9 | 43 |
| 7 | Materials characterisation by angle-resolved scanning transmission electron microscopy. Scientific Reports, 2016, 6, 37146. | 3.3 | 33 |
| 8 | Ultrathin Au-Alloy Nanowires at the Liquidâ€“Liquid Interface. Nano Letters, 2018, 18, 1903-1907. | 9.1 | 31 |
| 9 | Electrical Polarization in AlN/GaN Nanodisks Measured by Momentum-Resolved 4D Scanning Transmission Electron Microscopy. Physical Review Letters, 2019, 122, 106102. | 7.8 | 31 |
| 10 | Quantitative chemical evaluation of dilute GaNAs using ADF STEM: Avoiding surface strain induced artifacts. Ultramicroscopy, 2013, 129, 1-9. | 1.9 | 29 |
| 11 | Direct Measurement of Polarization-Induced Fields in GaN/AlN by Nano-Beam Electron Diffraction. Scientific Reports, 2016, 6, 28459. | 3.3 | 25 |
| 12 | A critical study: Assessment of the effect of silica particles from 15 to 500Ânm on bacterial viability. Environmental Pollution, 2013, 176, 292-299. | 7.5 | 24 |
| 13 | Influence of plasmon excitations on atomic-resolution quantitative 4D scanning transmission electron microscopy. Scientific Reports, 2020, 10, 17890. | 3.3 | 21 |
| 14 | Simultaneous Quantification of Indium and Nitrogen Concentration in InGaNAs Using HAADF-STEM. Microscopy and Microanalysis, 2014, 20, 1740-1752. | 0.4 | 20 |
| 15 | Quantitative Characterization of Nanometer-Scale Electric Fields via Momentum-Resolved STEM. Nano Letters, 2021, 21, 2018-2025. | 9.1 | 20 |
| 16 | Coherently Embedded Ag Nanostructures in Si: 3D Imaging and their application to SERS. Scientific Reports, 2014, 4, 4633. | 3.3 | 19 |
| 17 | Quantitative HAADF STEM of SiGe in presence of amorphous surface layers from FIB preparation. Ultramicroscopy, 2018, 184, 29-36. | 1.9 | 17 |
| 18 | Strain analysis from nano-beam electron diffraction: Influence of specimen tilt and beam convergence. Ultramicroscopy, 2018, 190, 45-57. | 1.9 | 17 |

| # | Article | IF | Citations |
|---|---|---|---|
| 19 | Using molecular dynamics for multislice TEM simulation of thermal diffuse scattering in AlGaN. Ultramicroscopy, 2018, 189, 124-135. | 1.9 | 16 |
| 20 | Influence of distortions of recorded diffraction patterns on strain analysis by nano-beam electron diffraction. Ultramicroscopy, 2019, 196, 74-82. | 1.9 | 15 |
| 21 | Optimization of NBED simulations for disc-detection measurements. Ultramicroscopy, 2017, 181, 50-60. | 1.9 | 13 |
| 22 | Bias-Controlled Optical Transitions in GaN/AlN Nanowire Heterostructures. ACS Nano, 2017, 11, 8758-8767. | 14.6 | 10 |
| 23 | Measurement of local crystal lattice strain variations in dealloyed nanoporous gold. Materials Research Letters, 2018, 6, 84-92. | 8.7 | 10 |
| 24 | Accurate measurement of strain at interfaces in 4D-STEM: A comparison of various methods. Ultramicroscopy, 2021, 221, 113196. | 1.9 | 10 |
| 25 | 4D-STEM at interfaces to GaN: Centre-of-mass approach & NBED-disc detection. Ultramicroscopy, 2021, 228, 113321. | 1.9 | 9 |
| 26 | Angle-resolved STEM using an iris aperture: Scattering contributions and sources of error for the quantitative analysis in Si. Ultramicroscopy, 2021, 221, 113175. | 1.9 | 8 |
| 27 | Towards the interpretation of a shift of the central beam in nano-beam electron diffraction as a change in mean inner potential. Ultramicroscopy, 2022, 236, 113503. | 1.9 | 6 |
| 28 | Angle-dependence of ADF-STEM intensities for chemical analysis of InGaN/GaN. Ultramicroscopy, 2022, 238, 113535. | 1.9 | 4 |
| 29 | Accuracy and precision of position determination in ISTEM imaging of BaTiO3. Ultramicroscopy, 2021, 227, 113325. | 1.9 | 2 |
| 30 | Quantitative characterization of nanometer-scale electric fields via momentum-resolved STEM. Microscopy and Microanalysis, 2021, 27, 2206-2207. | 0.4 | 0 |